

3.3V CMOS DUAL NEGATIVE-EDGE-TRIGGERED J-K FLIP-FLOP WITH CLEAR AND PRESET, 5 VOLT TOLERANT I/O

IDT74LVC112A

FEATURES:

- 0.5 MICRON CMOS Technology
- ESD > 2000V per MIL-STD-883, Method 3015; > 200V using machine model (C = 200pF, R = 0)
- Vcc = 3.3V ± 0.3V, Normal Range
- Vcc = 2.7V to 3.6V, Extended Range
- CMOS power levels (0.4 w W typ. static)
- · Rail-to-Rail output swing for increased noise margin
- · All inputs, outputs, and I/Os are 5V tolerant
- Supports hot insertion
- Available in TSSOP package

DRIVE FEATURES:

- · High Output Drivers: ±24mA
- · Reduced system switching noise

APPLICATIONS:

- 5V and 3.3V mixed voltage systems
- · Data communication and telecommunication systems

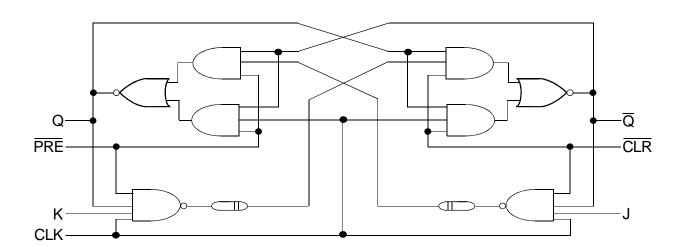
DESCRIPTION:

This dual negative-edge-triggered J-K flip-flop is built using advanced dual metal CMOS technology. A low level at the preset (\overline{PRE}) or clear (\overline{CLR}) inputs sets or resets the outputs, regardless of the levels of the other inputs. When \overline{PRE} and \overline{CLR} are inactive (high), data at the J and K inputs meeting the setup time requirements is transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the J and K inputs can be changed without affecting the levels at the outputs. The LVC112A can perform as a toggle flip-flop by tying J and K high.

Inputs can be driven from either 3.3V or 5V devices. This feature allows the use of this device as a translator in a mixed 3.3V/5V supply system.

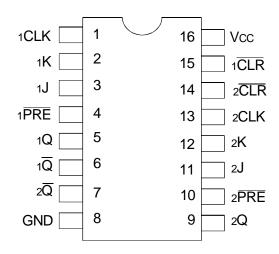
The LVC112A has been designed with a ± 24 mA output driver. This driver is capable of driving a moderate to heavy load while maintaining speed performance.

FUNCTIONAL BLOCK DIAGRAM



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PIN CONFIGURATION



TSSOP TOP VIEW

ABSOLUTE MAXIMUM RATINGS(1)

Symbol	Description	Max	Unit
VTERM	Terminal Voltage with Respect to GND	-0.5 to +6.5	٧
Tstg	Storage Temperature	-65 to +150	°C
lout	DC Output Current	-50 to +50	mA
lik lok	Continuous Clamp Current, VI < 0 or VO < 0	- 50	mA
lcc Iss	Continuous Current through each Vcc or GND	±100	mA

NOTE:

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

CAPACITANCE (TA = +25°C, F = 1.0MHz)

Symbol	Parameter ⁽¹⁾	Conditions	Тур.	Max.	Unit
CIN	Input Capacitance	VIN = 0V	4.5	6	pF
Соит	Output Capacitance	Vout = 0V	5.5	8	pF
CI/O	I/O Port Capacitance	VIN = 0V	6.5	8	pF

NOTE:

1. As applicable to the device type.

PIN DESCRIPTION

Pin Names	Description	
xCLK	CLK Inputs	
xCLR	Clear Inputs (Active LOW)	
xPRE	Preset Inputs (Active LOW)	
xJ, xK	Data Inputs	
xQ, x Q	Data Outputs	

FUNCTION TABLE(1)

	Inputs					puts
xPRE	xCLR	xCLK	хJ	хК	ДX	xQ
L	Н	Χ	Χ	Χ	Н	L
Н	L	Χ	Χ	Χ	L	Н
L	L	Χ	Х	Χ	H ⁽²⁾	H ⁽²⁾
Н	Н	\downarrow	L	L	Q ⁽³⁾	$\overline{Q}^{(4)}$
Н	Н	\downarrow	Н	L	Н	L
Н	Н	\downarrow	L	Н	L	Н
Н	Н	\	Н	Н	Toggle	
Н	Н	Н	Х	Х	Q ⁽³⁾	$\overline{Q}^{(4)}$

NOTES:

- 1. H = HIGH Voltage Level
 - L = LOW Voltage Level
 - X = Don't Care
 - ↓ = HIGH-to-LOW transition
- The output levels in this configuration may not meet the minimum levels for VOH. Furthermore, this configuration is unstable; that is, it does not persist when either PRE or CLR returns to its inactive (HIGH) level.
- 3. Level of Q before the indicated steady-state input conditions were established.
- 4 Complement of Q or level of $\overline{\mathbf{Q}}$ before the indicated steady-state input conditions were established.

DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE

Following Conditions Apply Unless Otherwise Specified:

Operating Condition: $TA = -40^{\circ}C$ to $+85^{\circ}C$

Symbol	Parameter	Test Coi	nditions	Min.	Typ. ⁽¹⁾	Max.	Unit
ViH	Input HIGH Voltage Level	Vcc = 2.3V to 2.7V		1.7	_	_	V
		Vcc = 2.7V to 3.6V		2	_	_	
VIL	Input LOW Voltage Level	Vcc = 2.3V to 2.7V		_	_	0.7	V
		Vcc = 2.7V to 3.6V		_	_	0.8	
lih lil	Input Leakage Current	VCC = 3.6V	VI = 0 to 5.5V	_	_	±5	μΑ
lozh lozl	High Impedance Output Current (3-State Output pins)	Vcc = 3.6V	Vo = 0 to 5.5V	_	_	±10	μΑ
loff	Input/Output Power Off Leakage	$VCC = 0V$, $VIN or VO \le 5.5V$			_	±50	μΑ
Vik	Clamp Diode Voltage	VCC = 2.3V, IIN = -18mA	Vcc = 2.3V, Iin = -18mA		-0.7	-1.2	V
VH	Input Hysteresis	Vcc = 3.3V		_	100	_	mV
Iccl Iccн Iccz	Quiescent Power Supply Current	Vcc = 3.6V, Vin = GND or Vcc		_	_	10	μΑ
∆lcc	Quiescent Power Supply Current Variation	One input at Vcc - 0.6V, other in	nputs at Vcc or GND	_	_	500	μΑ

NOTE:

OUTPUT DRIVE CHARACTERISTICS

Symbol	Parameter	Test Conditions ⁽¹⁾		Min.	Max.	Unit
Voн	Output HIGH Voltage	Vcc = 2.3V to 3.6V	IOH = - 0.1mA	Vcc-0.2	_	V
		Vcc = 2.3V	IOH = -6mA	2	_	
		Vcc = 2.3V	IOH = - 12mA	1.7	_	
		Vcc = 2.7V		2.2	_	
		Vcc = 3V		2.4	_	
		Vcc = 3V	Iон = - 24mA	2.2	_	
Vol	Output LOW Voltage	Vcc = 2.3V to 3.6V	IoL = 0.1mA		0.2	V
		Vcc = 2.3V	IoL = 6mA		0.4	
			IoL = 12mA	_	0.7	
		Vcc = 2.7V	IoL = 12mA		0.4	
		Vcc = 3V	IOL = 24mA	_	0.55	

NOTE:

^{1.} Typical values are at Vcc = 3.3V, +25°C ambient.

^{1.} VIH and VIL must be within the min. or max. range shown in the DC ELECTRICAL CHARACTERISTICS OVER OPERATING RANGE table for the appropriate Vcc range. TA = - 40°C to + 85°C.

OPERATING CHARACTERISTICS, Vcc = 3.3V ± 0.3V, Ta = 25°C

Symbol	Parameter	Test Conditions	Typical	Unit
CPD	Power Dissipation Capacitance per Flip-Flop	CL = 0pF, f = 10Mhz	24	pF

SWITCHING CHARACTERISTICS(1)

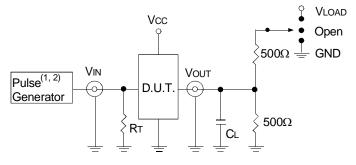
		Vcc =	= 2.7V	Vcc = 3.3	3V ± 0.3V	
Symbol	Parameter	Min.	Max.	Min.	Max.	Unit
fMAX		150	_	150	_	MHz
tplh	Propagation Delay	_	5.5	1	4.8	ns
tphl	\overline{XCLR} or \overline{PRE} to \overline{XQ}					
tplh	Propagation Delay	_	7.1	1	5.9	ns
tphl.	$x\overline{CLK}$ to xQ or x \overline{Q}					
tsu	Setup Time, Data before CLK↓	2.3	-	3.1	_	ns
tsu	Setup Time, PRE or CLR inactive	1.1	-	2.4	_	ns
tΗ	Hold Time, data after CLK↓	0.7	_	2.5	_	ns
tw	Pulse Width, CLK HIGH or LOW	3.3	_	3.3	_	ns
tsk(o)	Output Skew ⁽²⁾	_	_	_	500	ps

NOTES:

- 1. See TEST CIRCUITS AND WAVEFORMS. TA = -40° C to + 85° C.
- 2 Skew between any two outputs of the same package and switching in the same direction.

TEST CIRCUITS AND WAVEFORMS TEST CONDITIONS

Symbol	Vcc ⁽¹⁾ =2.5V±0.2V	Vcc ⁽²⁾ = 3.3V±0.3V & 2.7V	Unit
VLOAD	2 x Vcc	6	V
VIH	Vcc	2.7	V
VT	Vcc / 2	1.5	V
VLZ	150	300	mV
VHZ	150	300	mV
CL	30	50	pF



Test Circuit for All Outputs

LVC QUAD Link

DEFINITIONS:

CL = Load capacitance: includes jig and probe capacitance.

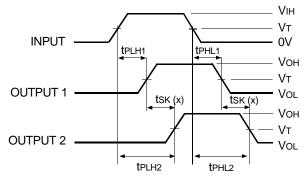
RT = Termination resistance: should be equal to ZouT of the Pulse Generator.

NOTES:

- 1. Pulse Generator for All Pulses: Rate \leq 10MHz; tr \leq 2ns; tr \leq 2ns.
- 2. Pulse Generator for All Pulses: Rate \leq 10MHz; tF \leq 2.5ns; tR \leq 2.5ns.

SWITCH POSITION

Test	Switch
Open Drain Disable Low Enable Low	VLOAD
Disable High Enable High	GND
All Other Tests	Open



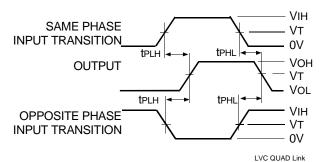
tSK(x) = |tPLH2 - tPLH1| or |tPHL2 - tPHL1|

LVC QUAD Link

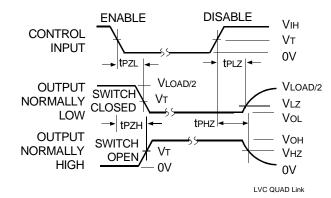
Output Skew - tsk(x)

NOTES:

- 1. For tsk(o) OUTPUT1 and OUTPUT2 are any two outputs.
- 2. For tsk(b) OUTPUT1 and OUTPUT2 are in the same bank.



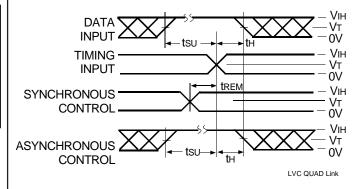
Propagation Delay



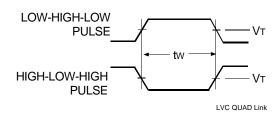
NOTE:

1. Diagram shown for input Control Enable-LOW and input Control Disable-HIGH.

Enable and Disable Times

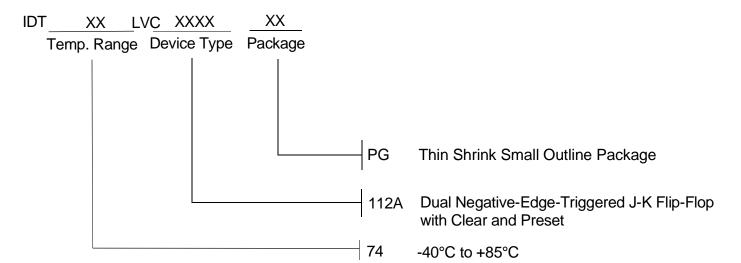


Set-up, Hold, and Release Times



Pulse Width

ORDERING INFORMATION





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